

Search Notes

Application/Control No.

10/811,172

Examiner

Ren L. Yan

Applicant(s)/Patent under
Reexamination

CARTER ET AL.

Art Unit

2854

SEARCHED

Class	Subclass	Date	Examiner
399	401	2/3/06	R. Yan
	402		
271	902		
101	229		
	230		
	231		
	232		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR